# life.augmented

## STFU16N65M2

## N-channel 650 V, 0.32 Ω typ., 11 A MDmesh<sup>™</sup> M2 Power MOSFET in a TO-220FP ultra narrow leads package

Datasheet - production data

#### Features

Order code	VDS	R <sub>DS(on)</sub> max	ΙD
STFU16N65M2	650 V	0.36 Ω	11 A

- Extremely low gate charge
- Excellent output capacitance (Coss) profile
- 100% avalanche tested
- Zener-protected

### **Applications**

• Switching applications

## Description

This device is an N-channel Power MOSFET developed using MDmesh<sup>™</sup> M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

#### Table 1: Device summary

Order code	Marking	Package	Packaging
STFU16N65M2	16N65M2	TO-220FP ultra narrow leads	Tube

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This is information on a product in full production.



### Figure 1: Internal schematic diagram



#### Contents

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## 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
Vgs	Gate-source voltage	± 25	V
ID	Drain current (continuous) at T <sub>C</sub> = 25 °C	11 <sup>(1)</sup>	А
lo	Drain current (continuous) at Tc = 100 °C	6.9 <sup>(1)</sup>	А
I <sub>DM</sub> <sup>(2)</sup>	Drain current (pulsed)	44 <sup>(1)</sup>	А
Ртот	Total dissipation at $T_C = 25 \text{ °C}$	25	W
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; $T_C$ = 25 °C)	2500	V
dv/dt (3)	Peak diode recovery voltage slope	15	V/ns
dv/dt (4)	MOSFET dv/dt ruggedness	50	v/ns
T <sub>stg</sub>	Storage temperature range	55 to 150	°C
Tj	Operating junction temperature range	-55 to 150	C

#### Notes:

<sup>(1)</sup>Limited by maximum junction temperature..

<sup>(2)</sup>Pulse width limited by safe operating area.

 $^{(3)}I_{SD} \leq$  11 A, di/dt  $\leq$  400 A/µs; V\_DSpeak < V(BR)DSS, V\_DD=400 V  $^{(4)}V_{DS} \leq$  520 V

#### Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case	5	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	62.5	°C/W

#### Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax})$	1.9	А
Eas	Single pulse avalanche energy (starting $T_j = 25^{\circ}C$ , $I_D = I_{AR}$ ; $V_{DD} = 50 \text{ V}$ )	360	mJ



#### 2 **Electrical characteristics**

(Tc = 25 °C unless otherwise specified)

Table 5: On /off states						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	650			V
	Zoro goto voltago	$V_{GS} = 0 V, V_{DS} = 650 V$			1	μA
IDSS	IDSS Zero gate voltage drain current	$V_{GS} = 0 V, V_{DS} = 650 V,$ $T_{C} = 125 °C^{(1)}$			100	μA
Igss	Gate-body leakage current	$V_{DS} = 0 V$ , $V_{GS} = \pm 25 V$			±10	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 5.5 \text{ A}$		0.32	0.36	Ω

#### Notes:

<sup>(1)</sup>Defined by design, not subject to production test.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	718	-	pF
Coss	Output capacitance	$V_{DS} = 100 V, f = 1 MHz,$	-	32	-	pF
Crss	Reverse transfer capacitance	V <sub>GS</sub> = 0 V	-	1.1	-	pF
Coss eq. <sup>(1)</sup>	Equivalent output capacitance	$V_{\text{DS}}=0 \text{ to } 520 \text{ V}, \text{ V}_{\text{GS}}=0 \text{ V}$	-	189	-	pF
Rg	Intrinsic gate resistance	f = 1 MHz open drain	-	5.2	-	Ω
Qg	Total gate charge	$V_{DD} = 520 \text{ V}, \text{ I}_{D} = 11 \text{ A},$	-	19.5	-	nC
Q <sub>gs</sub>	Gate-source charge	$V_{GS} = 0$ to 10 V	-	4	-	nC
$Q_{gd}$	Gate-drain charge	(see Figure 15: "Test circuit for gate charge behavior"	-	8.3	-	nC

#### Table 6: Dynamic

#### Notes:

 $^{(1)}C_{oss eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$ increases from 0 to 80% VDSS

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	$V_{DD} = 325 \text{ V}, \text{ I}_{D} = 5.5 \text{ A},$	-	11.3	-	ns
tr	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$	-	8.2	-	ns
td(off)	Turn-off delay time	(see Figure 14: "Test circuit for resistive load switching times"	-	36	-	ns
tr	Fall time	and Figure 19: "Switching time waveform")	-	11.3	-	ns

Table 7: Switching times



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#### Electrical characteristics

Table 8: Source drain diode						
Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
Isd	Source-drain current		-		11	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		44	А
Vsd <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 11 A, V <sub>GS</sub> = 0 V	-		1.6	V
trr	Reverse recovery time	I <sub>SD</sub> = 11 A, di/dt = 100 A/µs,	-	342		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 V$	-	3.5		μC
IRRM	Reverse recovery current	(see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	20.4		A
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 11 A, di/dt = 100 A/µs,	-	458		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, \text{ T}_{j} = 150 \text{ °C}$	-	4.6		μC
Irrm	Reverse recovery current	(see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	20.5		A

#### Notes:

<sup>(1)</sup>Pulse width limited by safe operating area.

 $^{(2)}\text{Pulsed:}$  pulse duration = 300 µs, duty cycle 1.5%









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#### **Electrical characteristics**







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## 3 Test circuits







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## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.

## 4.1 TO-220FP ultra narrow leads package information



Figure 20: TO-220FP ultra narrow leads package outline



#### Package mechanical data

#### STFU16N65M2

nechanical data	echanical data STFU16N65M2				
Т	able 9: TO-220FP ultra narr	row leads mechanical of	data		
Dim		mm			
Dim.	Min.	Тур.	Max.		
A	4.40		4.60		
В	2.50		2.70		
D	2.50		2.75		
E	0.45		0.60		
F	0.65		0.75		
F1	-		0.90		
G	4.95		5.20		
G1	2.40	2.54	2.70		
Н	10.00		10.40		
L2	15.10		15.90		
L3	28.50		30.50		
L4	10.20		11.00		
L5	2.50		3.10		
L6	15.60		16.40		
L7	9.00		9.30		
L8	3.20		3.60		
L9	-		1.30		
Dia.	3.00		3.20		

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## 5 Revision history

Table 10: Document revision history

Date	Revision	Changes
03-Apr-2017	1	Initial release



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